

<b>Notice of References Cited</b>	Application/Control No. 10/661,534	Applicant(s)/Patent Under Reexamination KATAYAMA ET AL.	
	Examiner Devona E. Faulk	Art Unit 2615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,883,963	03-1999	Tonella, Maurizio	381/104
*	B	US-6,360,187	03-2002	Hermann, Thomas J.	702/191
*	C	US-2002/0052182	05-2002	Mayuzumi, Ichiko	455/41
*	D	US-6,980,092	12-2005	Turnbull et al.	340/425.5
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.